

Optimal Dithering Pattern for 3DP

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Outline

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Objective

Development of a *halftoning technique* for local composition control in 3DP

Criteria:

- Minimization of low frequency textures
- Minimum run-length requirement
- Limit of 3DP machine's pattern memories

Overview of Digital Halftoning

Halftone approximation:

Simulation of continuous-tone gray scales for *bi-level* displays and hardcopy devices

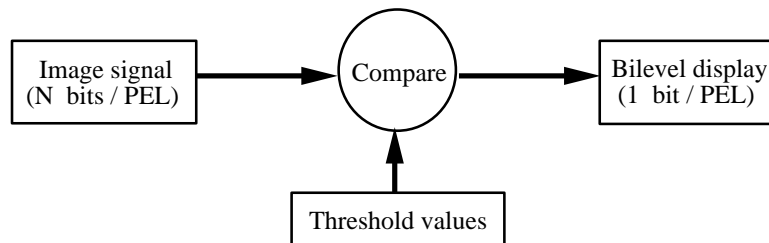


Figure: Basic halftoning process

- Ordered dither approach: A set of *ordered* threshold values τ_{ij} are used.
 - Clustered-dot ordered dither:
 - * On-PELs are *adjacent* to each other.
 - * *Outward growing pattern*
 \implies create an effect of increasing dot size.
 - * Preferred if devices are poor at accommodating isolated on-PELs, e.g. halftone laser printer.
 - * Apparent *low frequency textures* in an area of uniform gray levels.

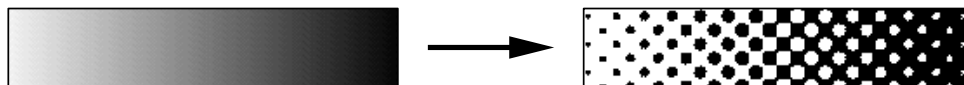


Figure: Gray scale ramp: clustered-dot ordered dither

- Dispersed-dot ordered dither:
 - * On-PELs are *not* necessarily *adjacent* to each other.
 - * Yield *high frequency* fidelity.

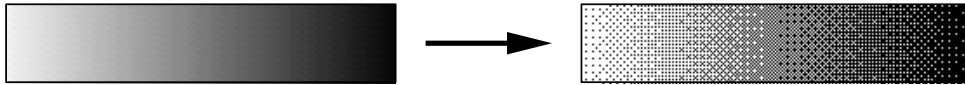


Figure: Gray scale ramp: dispersed-dot ordered dither

- Error diffusion algorithm: Spread halftone approximation error over neighboring PELs to *minimize the global error*.

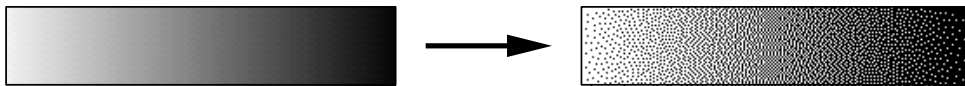


Figure: Gray scale ramp: error diffusion approach

Comments on 3DP application:

- Clustered-dot ordered dither:
 - Less possibility of missing droplet placements
 - Undesirable low frequency texture patterns
- Dispersed-dot ordered dither:
 - High frequency fidelity
 \implies desirable material distribution
 - Minimum run-length requirement
- Error diffusion algorithm:
 - Precise description of material composition
 - Hard to utilize pattern memories of 3DP machine

Bayer's Algorithm

- **Given:** The *size*, m , of a 2^m by 2^m dither matrix
 \implies The number of gray levels = $2^m \times 2^m + 1$.
- **Find:** A rule for *optimum dither pattern* i.e., the optimum *order* in which new dots are added to the halftone cell as gray scale is varied.
- **Optimality:** Minimization of *low frequency texture* in an area of *uniform* gray scale.

$$\mathbf{T}^{(2m)} = \begin{pmatrix} 4\mathbf{T}^{(m)} & 4\mathbf{T}^{(m)} + 2\mathbf{U}^{(m)} \\ 4\mathbf{T}^{(m)} + 3\mathbf{U}^{(m)} & 4\mathbf{T}^{(m)} + \mathbf{U}^{(m)} \end{pmatrix}$$

where, $\mathbf{U}^{(m)} = \begin{pmatrix} 1 & 1 & \dots & 1 \\ 1 & 1 & \dots & 1 \\ \cdot & \cdot & \dots & \cdot \\ 1 & 1 & \dots & 1 \end{pmatrix}$ and $\mathbf{T}^{(2)} = \begin{pmatrix} 0 & 2 \\ 3 & 1 \end{pmatrix}$

Example: $m = 2 \implies 4 \times 4 + 1 = 17$ gray levels

$$\mathbf{T}^{(4)} = \begin{pmatrix} 4\mathbf{T}^{(2)} & 4\mathbf{T}^{(2)} + 2\mathbf{U}^{(2)} \\ 4\mathbf{T}^{(2)} + 3\mathbf{U}^{(2)} & 4\mathbf{T}^{(2)} + \mathbf{U}^{(2)} \end{pmatrix} = \begin{pmatrix} 0 & 8 & 2 & 10 \\ 12 & 4 & 14 & 6 \\ 3 & 11 & 1 & 9 \\ 15 & 7 & 13 & 5 \end{pmatrix}$$

3DP Application

(1) Extraction of 1D Patterns

Find all 1D patterns necessary to describe those $2^{2m} + 1$ number of 2D Bayer's dither patterns.

Example: If $m = 2$, 12 1D patterns are necessary to describe 17 2D dither patterns.

⇒ 0000 1000 0100 0010 0001 1010
0101 1110 1101 1011 0111 1111

(2) Minimum Run-Length Requirement

Among those 1D patterns, select patterns that satisfy the minimum run-length requirement.

Example: If $m = 2$ & $minRunLen = 2$, only 5 patterns (1110, 1101, 1011, 0111, 1111) satisfy the minimum run-length requirement.

⇒ 0000 & 1111 would be done with transition bits, and hence 4 pattern memories may be needed in this case

⇒ *Only high* intensity levels (levels 15, 16, 17) and the lowest one (level 1) can be described by such patterns and transition instructions.

0000	1111	1111	1111
0000	1101	1111	1111
0000	1111	1111	1111
0000	0111	0111	1111
level 1	level 15	level 16	level 17

Minimum Run-Length Requirement (continued)

Construct a $2^m \times \text{minRunLen}$ by 2^m halftone cell by replicating each PEL of the 2^m by 2^m halftone cell minimum run-length times along the fast-axis direction.

1 0 1 0	0 1 0 0	1 0 1 0	0 0 0 0	→	1 1 0 0 1 1 0 0	0 0 1 1 0 0 0 0	1 1 0 0 1 1 0 0	0 0 0 0 0 0 0 0
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Figure: Level 6 ($m = 2$, $\text{minRunLen} = 2$)

- The modified halftone cell still provides $2^{2m} + 1$ dither patterns.
- All the associated 1D patterns will satisfy the minimum run-length requirement.

Example: 12 1D patterns ($m = 2$, $\text{minRunLen} = 2$)

00000000	11000000	00110000	00001100	00000011	11001100
00110011	11111100	11110011	11001111	00111111	11111111

(3) Pattern Memory

If the number N of 1D patterns^a is greater than the number P of pattern memories of 3DP machine, we consider $\binom{N}{P}$ number of combinations of such 1D patterns.

Example: ($m = 2$, $minRunLen = 2$, $N = 10$)

Set $P = 8$, then $\binom{10}{8} = 45$ possible combinations exist.

00000011 00001100 00110000 11000000 00110011

11001100 11001111 11111100 00000000 11111111

Figure: One possible combination ($m = 2$, $minRunLen = 2$)
 \implies 14 dithering patterns can be described.

\implies Levels: 1, 2, 3, 4, 5, 6, 7, 8, 9, 10, 11, 12, 13, 17

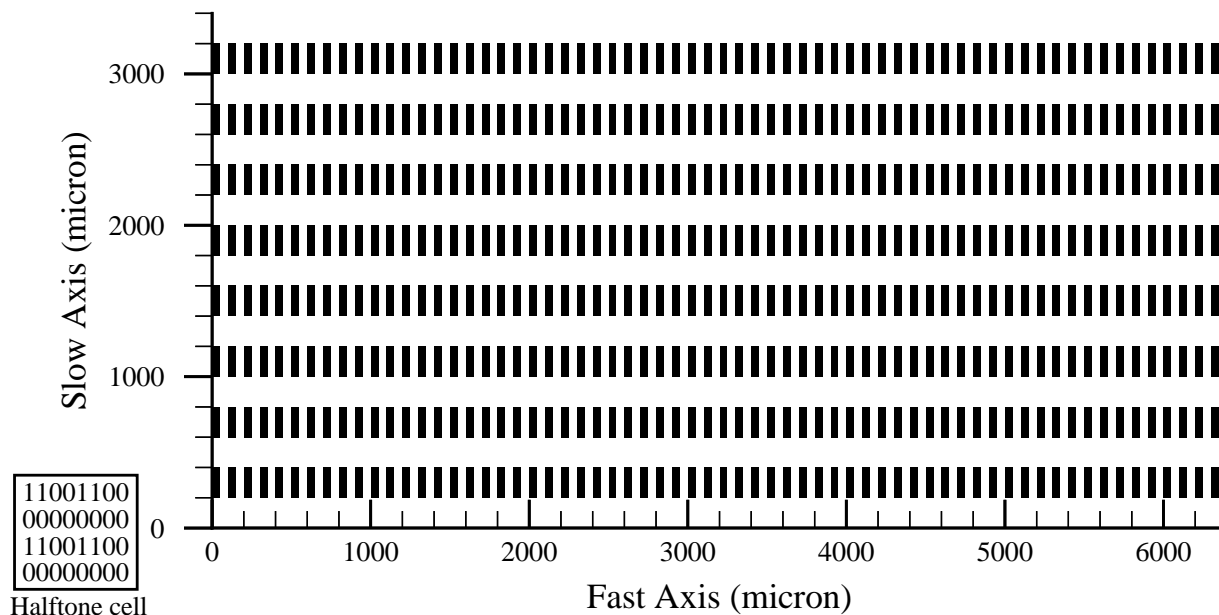


Figure: Level 5 (PEL size = $25\mu \times 200\mu$)

^aexcluding 000...00 and 111...11

Generalized Bayer's Algorithm

- **Given:**

- m : parameter that controls the size (2^m by 2^m) of threshold matrix $[\tau_{ij}]$
- L : specified minimum run-length
- $r_0 (= \Delta y / \Delta x)$: aspect ratio of PEL

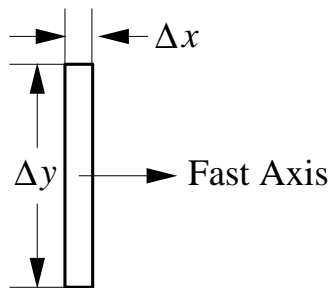


Figure: Non-square PEL

- **Compute:** 2^m by 2^m threshold matrix $[\tau_{ij}]$ satisfying Bayer's criteria for PELs of aspect ratio $r = \Delta Y / \Delta X = r_0 / L$

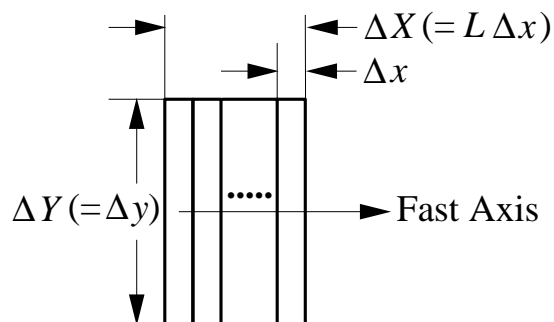


Figure: L times replicated PEL

Generalized Bayer's Algorithm (continued)

- Bayer's criterion

Minimization of the *longest finite wavelength* of the nonzero sinusoidal components that describe the dot pattern of an area of uniform intensity.

- Construction of threshold matrix $[\tau_{ij}]$

Suppose that an area of uniform intensity is represented by repeating both horizontally and vertically a 2^m by 2^m subarray of rectangular elements of width ΔX , height ΔY .

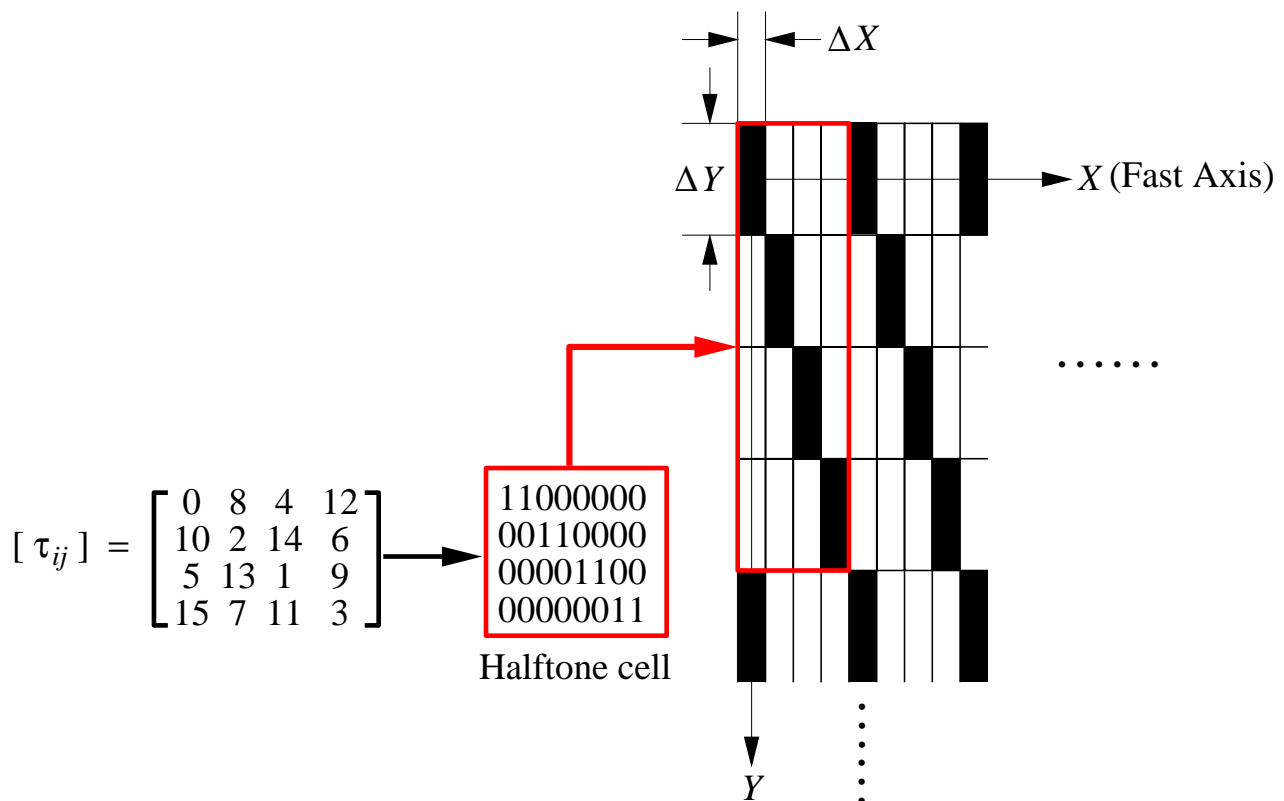


Figure: An area of uniform intensity (level 5, $m = 2$, $r = 4$)

Construction of threshold matrix (continued)

Let $I(X, Y)$ be the intensity value ($= 0$ or 1) at $(X, Y) = (k\Delta X, l\Delta Y)$, where integers $k, l \in [0, 2^m)$, then:

$$I(X + 2^m \Delta X, Y) = I(X, Y + 2^m \Delta Y) = I(X, Y), \quad (1)$$

i.e.,

$$I((k + 2^m)\Delta X, l\Delta Y) = I(k\Delta X, (l + 2^m)\Delta Y) = I(k\Delta X, l\Delta Y). \quad (1')$$

The basic subarray can be specified by all combinations of such k, l and hence,

$$I(X, Y) = I(k\Delta X, l\Delta Y) := \sum_{u=-2^{m-1}+1}^{2^m-1} \sum_{v=-2^{m-1}+1}^{2^m-1} J\left(\frac{u}{2^m \Delta X}, \frac{v}{2^m \Delta Y}\right) e^{-i2\pi\left(\frac{uk+vl}{2^m}\right)} \quad (2)$$

where,

$$J\left(\frac{u}{2^m \Delta X}, \frac{v}{2^m \Delta Y}\right) := \frac{1}{2^{2m}} \sum_{k=0}^{2^m-1} \sum_{l=0}^{2^m-1} I(k\Delta X, l\Delta Y) e^{i2\pi\left(\frac{uk+vl}{2^m}\right)}. \quad (3)$$

Construction of threshold matrix (continued)

The real part of each term in Eq. (2) is a sinusoidal plane wave with an *amplitude* A_{uv} , given by

$$A_{uv} = \sqrt{J\left(\frac{u}{2^m \Delta X}, \frac{v}{2^m \Delta Y}\right) J\left(\frac{-u}{2^m \Delta X}, \frac{-v}{2^m \Delta Y}\right)} \quad (4)$$

and a *wave length* λ_{uv} measured at right angles in the wave front, given by

$$\lambda_{uv} = \frac{2^m \Delta Y}{\sqrt{(ru)^2 + v^2}}, \quad r \geq 1 \quad (5)$$

in XY -plane.

An *index of texture* Λ in a uniform area is defined by

$$\Lambda := \max_{-M+1 \leq u, v \leq M} \{\lambda_{uv} | A_{uv} \neq 0, \lambda_{uv} < \infty\}, \quad (6)$$

where $M = 2^{m-1}$.

Example: For $m = 2, r = 4 \implies \underline{\Lambda = 4\Delta Y = \lambda_{0,-1} = \lambda_{01} > \lambda_{02} > \lambda_{-1,0} = \lambda_{10}$

$> \lambda_{-1,-1} = \lambda_{-1,1} = \lambda_{1,-1} = \lambda_{11} > \lambda_{-1,2} = \lambda_{1,2} > \lambda_{20} > \lambda_{2,-1} = \lambda_{21} > \lambda_{22}$

\implies Our problem consists of choosing a sequence of 2^{2m} positions within 2^m by 2^m lattice that minimize Λ for each level of intensity.

Construction of threshold matrix (continued)

Remark: From Eq.'s (3) and (5), we can have $\Lambda < 2^m \Delta Y$ if and only if $J_{0,-1} = J_{01} = 0$, where $J_{uv} := J(\frac{u}{2^m \Delta X}, \frac{v}{2^m \Delta Y})$. However, we can not have $\Lambda < 2^m \Delta Y$ for *two successive* values of N_{dot} , where N_{dot} is the number of black dots in the basic 2^m by 2^m lattice.

\implies Suppose that J_{uv} is zero for some value of N_{dot} , then adding one dot to an empty position $(X_\alpha, Y_\alpha) = (k_\alpha \Delta X, l_\alpha \Delta Y)$ results in adding a nonzero term to Eq. (3). Thus J_{uv} can not equal zero for $(N_{dot} + 1)$ black dots.

\implies We can, however, make $\Lambda < 2^m \Delta Y$ for $(N_{dot} + 2)$ black dots by computing *appropriate positions* (X_α, Y_α) and (X_β, Y_β) for $(N_{dot} + 1)^{\text{th}}$ and $(N_{dot} + 2)^{\text{th}}$ black dots, respectively.

Construct-Threshold-Matrix ($[\tau_{ij}]$)

1. **for each** $i, j \in [0, 2^m)$ **set** $\tau_{ij} \leftarrow 0, d_{ij} \leftarrow 0$
▷ Initialize threshold matrix $[\tau_{ij}]$, dither pattern $[d_{ij}]$.
2. **set** $counter \leftarrow 0$
3. **while** ($\exists(\alpha, \beta) | d_{\alpha\beta} = 0$) **do**:
▷ Repeat until every dither pattern is computed.
4. **set** $n \leftarrow 0$
5. **for each** $i, j \in [0, 2^m)$ **such that** $d_{ij} = 0$ **do**:
6. **set** $d_{ij} \leftarrow 1$ ▷ Add a dot to an empty position.
7. **for each** $k, l \in [0, 2^m)$ **such that** $d_{kl} = 0$ **and**
 $(2^m k + l > 2^m i + j)$ **do**:
8. **set** $d_{kl} \leftarrow 1$
 ▷ Add another dot to an empty position.
9. **insert** ij, kl **into** $List[n]$
10. **for each** $u, v \in (-2^{m-1}, 2^{m-1}]$ **and**
 $(u \neq 0 \vee v \neq 0)$ **do**:
11. **compute** J_{uv} ▷ Compute Fourier coeff's.
12. **if** $J_{uv} \neq 0$ **do**:
13. **compute** $\lambda_{uv}, A_{uv} \implies$ **let** $Wave$
14. **insert** $Wave$ **into** $List[n]$
15. **reset** $d_{kl} \leftarrow 0$ ▷ For the next trial (k, l)
16. **reset** $d_{ij} \leftarrow 0$ ▷ For the next trial (i, j)
17. **set** $n \leftarrow n + 1$
18. **Find-Optimal-Position** ($List[0, 1 \dots n - 1], ij, kl$)
 ▷ Find (ij, kl) satisfying Bayer's criteria.
19. **set** $\tau_{ij} \leftarrow counter, \tau_{kl} \leftarrow counter + 1,$
 $\frac{counter \leftarrow counter + 2}{}$
 ▷ Assign threshold values.
20. **set** $d_{ij} \leftarrow 1, d_{kl} \leftarrow 1$
 ▷ Add two successive dots to optimal positions.

Find-Optimal-Position ($List[0, 1, \dots, n - 1], i^*j^*, k^*l^*$)

1. **for** $\alpha \leftarrow 0$ **to** $n - 1$ **sort** λ_{uv} 's **in** $List[\alpha]$
 - ▷ For each trial pair of dot positions, sort λ_{uv} 's in descending order
2. **for each** $List[\alpha]$ & $List[\beta]$ **do**:
3. **if** Which-Is-Better ($List[\alpha], List[\beta]$) = $List[\alpha]$
 - ▷ Compare two pairs of trial dot positions.
 - then remove** $List[\beta]$
4. **else remove** $List[\alpha]$
5. **set** $i^*j^*, k^*l^* \leftarrow ij, kl$ **in** $List[0]$
 - ▷ Optimal positions for two successive dots d_{ij}, d_{kl} .

Which-Is-Better ($List[\alpha], List[\beta]$)

1. **set** $Wave_\alpha \leftarrow head(List[\alpha]), Wave_\beta \leftarrow head(List[\beta])$
2. **while** ($Wave_\alpha$ & $Wave_\beta \neq NIL$) **do**:
3. **set** $\lambda_\alpha \leftarrow \lambda$ **of** $Wave_\alpha, \lambda_\beta \leftarrow \lambda$ **of** $Wave_\beta$
4. **if** $\lambda_\alpha < \lambda_\beta$ **then return** $List[\alpha]$
5. **else if** $\lambda_\alpha > \lambda_\beta$ **then return** $List[\beta]$
6. **else do**:
7. **set** $Wave_\alpha \leftarrow next(Wave_\alpha) Wave_\beta \leftarrow next(Wave_\beta)$
8. **reset** $Wave_\alpha \leftarrow head(List[\alpha]), Wave_\beta \leftarrow head(List[\beta])$
9. **while** ($Wave_\alpha$ & $Wave_\beta \neq NIL$) **do**:
10. **set** $A_\alpha \leftarrow A$ **of** $Wave_\alpha, A_\beta \leftarrow A$ **of** $Wave_\beta$
11. **if** $A_\alpha < A_\beta$ **then return** $List[\alpha]$
12. **else if** $A_\alpha > A_\beta$ **then return** $List[\beta]$
13. **else do**:
14. **set** $Wave_\alpha \leftarrow next(Wave_\alpha) Wave_\beta \leftarrow next(Wave_\beta)$
15. **return** $List[\alpha]$

Example For $r_0 = 8, L = 2 \implies r = 4$:

(1) $m = 1$:

$$\begin{bmatrix} 0 & 2 \\ 3 & 1 \end{bmatrix} \quad \begin{bmatrix} 0 & 2 \\ 3 & 1 \end{bmatrix}$$

(2) $m = 2$:

$$\begin{bmatrix} 0 & 8 & 4 & 12 \\ 10 & 2 & 14 & 6 \\ 5 & 13 & 1 & 9 \\ 15 & 7 & 11 & 3 \end{bmatrix} \quad \begin{bmatrix} 0 & 8 & 2 & 10 \\ 12 & 4 & 14 & 6 \\ 3 & 11 & 1 & 9 \\ 15 & 7 & 13 & 5 \end{bmatrix}$$

(3) $m = 3$:

$$\begin{bmatrix} 0 & 34 & 44 & 56 & 4 & 48 & 8 & 38 \\ 40 & 62 & 12 & 28 & 52 & 22 & 16 & 24 \\ 2 & 36 & 10 & 50 & 6 & 32 & 58 & 46 \\ 60 & 54 & 42 & 20 & 26 & 30 & 14 & 18 \\ 1 & 49 & 9 & 39 & 5 & 35 & 45 & 57 \\ 53 & 23 & 17 & 25 & 41 & 63 & 13 & 29 \\ 3 & 33 & 59 & 47 & 7 & 37 & 11 & 51 \\ 27 & 31 & 15 & 19 & 61 & 55 & 43 & 21 \end{bmatrix}$$

$$\begin{bmatrix} 0 & 32 & 8 & 40 & 2 & 34 & 10 & 42 \\ 48 & 16 & 56 & 24 & 50 & 18 & 58 & 26 \\ 12 & 44 & 4 & 36 & 14 & 46 & 6 & 38 \\ 60 & 28 & 52 & 20 & 62 & 30 & 54 & 22 \\ 3 & 35 & 11 & 43 & 1 & 33 & 9 & 41 \\ 51 & 19 & 59 & 27 & 49 & 17 & 57 & 25 \\ 15 & 47 & 7 & 39 & 13 & 45 & 5 & 37 \\ 63 & 31 & 55 & 23 & 61 & 29 & 53 & 21 \end{bmatrix}$$

(a) Generalized algorithm

(b) Original algorithm

Example: ($m = 2, L = 2, r_0 = 8 \implies r = 4$)

$$\underline{\Lambda = \frac{2\Delta Y}{\sqrt{5}} = \lambda_{-1,2} = \lambda_{12} > \lambda_{2,-1} = \lambda_{21}} \quad (7)$$

We note:

$$\underline{\Lambda = 2\Delta Y} = \lambda_{02} > \lambda_{-1,0} = \lambda_{10} > \lambda_{-1,2} = \lambda_{12} \quad (8)$$

if original Bayer's $[\tau_{ij}]$ is used.

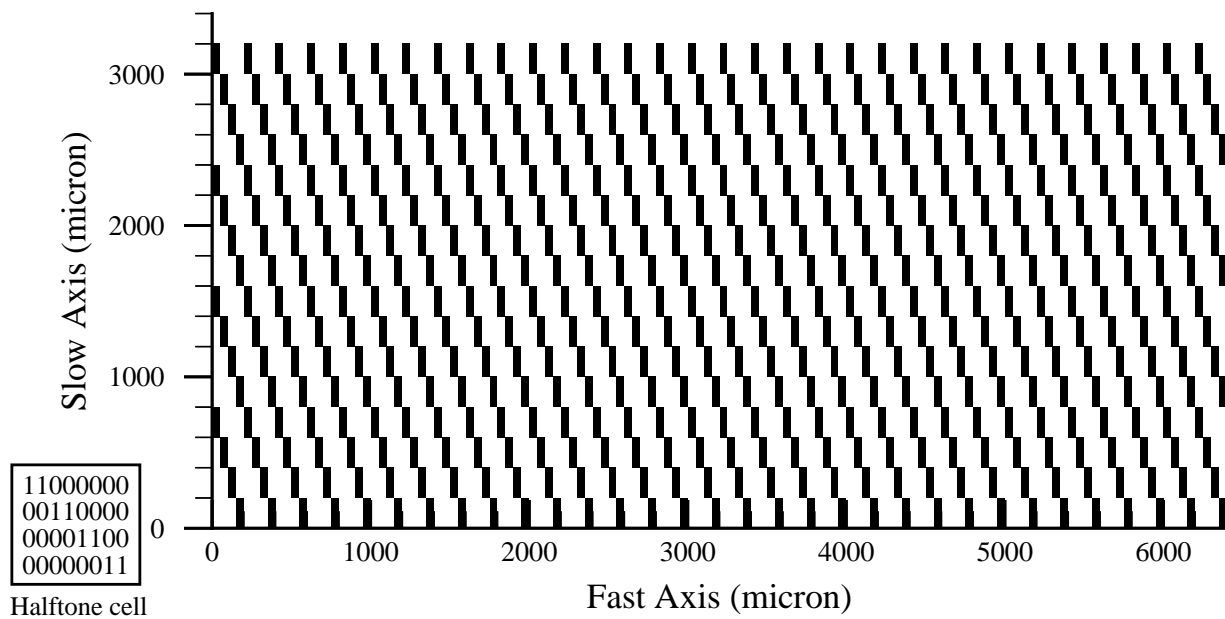
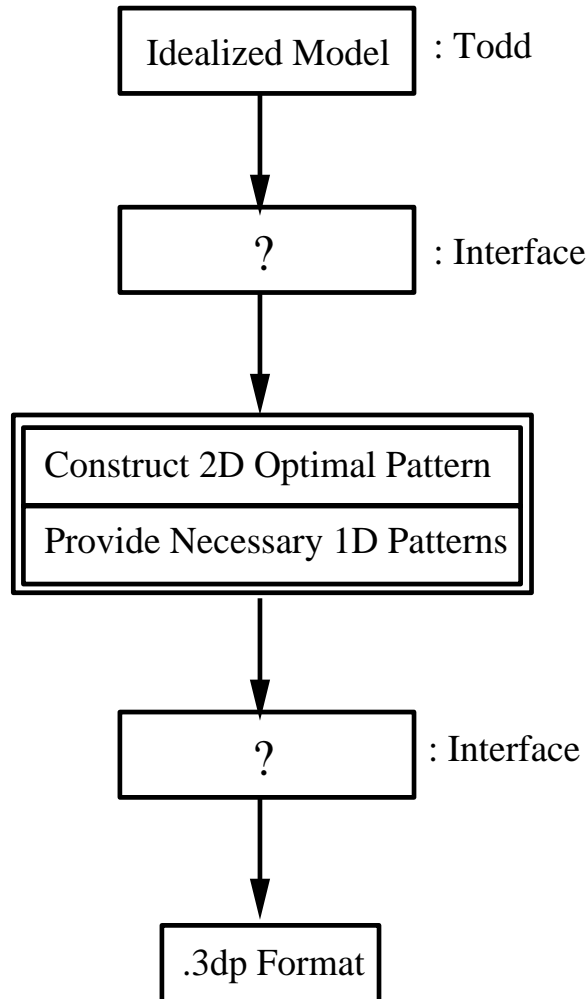


Figure: Level 5 (PEL size = $25\mu \times 200\mu$)

Summary



- Extension to optimal dithering for composition of *arbitrary* number of materials.
⇒ Utilize *color halftoning* technique based on Bayer's criteria.
- 3D halftoning for a volume of uniform material composition